

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/708,691	SUFKA ET AL.
	Examiner	Art Unit
	EDMUND H. LEE	1732

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
264	154,156	5/17/2007	EHL
	275,263		
	272.15		
264/272.16			